

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT
(IECEE) CB SCHEME**CB TEST CERTIFICATE**

Product	Current controlled dimmable independent LED Driver
Name and address of the applicant	HEP Tech Co., Ltd. No. 20, Jingke 7th Rd., Nantun Dist., 40852 Taichung City, Taiwan
Name and address of the manufacturer	HEP GmbH Ramsloh 10, 58579 Schalksmühle, Germany
Name and address of the factory	HEP GmbH Ramsloh 10, 58579 Schalksmühle, Germany
<i>When more than one factory</i>	<input checked="" type="checkbox"/> Additional information on page 2
Ratings and principal characteristics	Product data Ratings: Un= 220-240 V; 0/50-60 Hz; IP 20; Class II; SELV; max. enclosure temperature under abnormal or fault conditions 110 °C For specific electrical rating refer to test report.
Trademark / Brand (if any)	HEP GROUP®
Customer's Testing Facility (CTF) Stage used	CTF Stage 2
Model / Type Ref.	LEDC30W1050NLR-Z, LEDC30W1050NLR-Z-W, LEDC45W1050NLR-Z, LEDC45W1050NLR-Z-D4I, LEDC45W1050NLR-Z-W, LEDC60W1750NLR-Z, LEDC60W1750NLR-Z-D4I and LEDC60W1750NLR-Z-W
Additional information	<input type="checkbox"/> Additional information on page 2
A sample of the product was tested and found to be in conformity with	IEC 61347-1:2015, IEC 61347-1:2015/AMD1:2017, IEC 61347-2-13:2014, IEC 61347-2-13:2014/AMD1:2016 and IEC 62384:2020
As shown in the Test Report Ref. No. which forms part of this Certificate	3432131.50, 3432131.51

This CB Test Certificate is issued by the National Certification Body

DEKRA Certification B.V.
Meander 1051
6825 MJ Arnhem
Netherlands

Date: 30 January 2024


Signature: T. Baltzer 



Ref. Certif. No.

NL-103766

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Additional factory

Weisen Electronic Co. Ltd.
No. 3 Yangchun Rd., Jinwan Dist., 519040 Zhuhai City Guangdong, China

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